LASER INTERFEROMETER GRAVITATIONAL WAVE OBSERVATORY

SPECIFICATION

E050190 -A- D
Drawing No Rev. Group

Sheet 1 of 2

Final Polish, LASTI End Test Mass (ETM)

					APPROVALS		
AUTHOR:	CHECKED:	DATE	DCN NO.	REV	DATE		
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Applicable Documents

LIGO

LIGO-D040431-B Quad ETM Silica Test Mass

<u>LIGO-D030265-</u>A Fused Silica Blank LASTI Test Mass
<u>LIGO-E030309-</u>A Fused Silica Blank, LASTI Test Mass, R&D
LIGO-E050191-A Shape and Polish LASTI ETM Blank

MIL-PRF-13830B General Specification Governing the Manufacture, Assembly, and Inspection of

Optical Components for Fire Control Instruments

Requirements

Physical Configuration

According to

LIGO-D040431 Quad ETM Silica Test Mass, X dimension 200.0 ± 0.5 inches

Fabricate from

LIGO-E050191 Shape and Polish LASTI ETM blank

LIGO-E030309 Fused Silica Blank, LASTI Test Mass, R&D

Optical Surface Figure, Sides 1 and 2 - FLAT. Measured over the central 120 mm diameter

Surface 1: Flat to $\lambda/10$ peak to valley, measured at 633 nm

Radius of curvature: >150 km

Surface 2: Flat to $\lambda/10$ measured at 633 nm

Radius of curvature: > ±20 km

Surface Error, High Spatial Frequency: "microroughness" measured over the central 120 mm diameter

Surface 1 HSF error $\sigma_{rms} \leq 0.2$ nanometers

Surface 2: not specified

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Scratches, Sleeks and Point defects

Scratches, sleeks and point defects are evaluated according to MIL-PRF-13830B

Side 1

Within the central 20mm diameter: 10/5 Within the central 120 mm diameter: 20/10 Outside the central 120 mm diameter: 40/20

Side 2

Within the central 120 mm diameter: 40/20

Inspection

Table 1: Inspections

Specification	Test Method	Data Delivered
Scratches and Point defects, side	Visual Inspection	Certification
one		
Figure, side one	Interferometry	Surface phase map
Surface Errors - High Spatial	Interferometry	Surface maps for 3 central locations. Numerical values
frequency, side one		included with certification

Orientation: For the purpose of phase maps the substrate shall be oriented such that the point of minimum thickness shall be at the top center of the data.